

Description

The AP420N03SLG5 uses advanced **APM-SGT V** technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

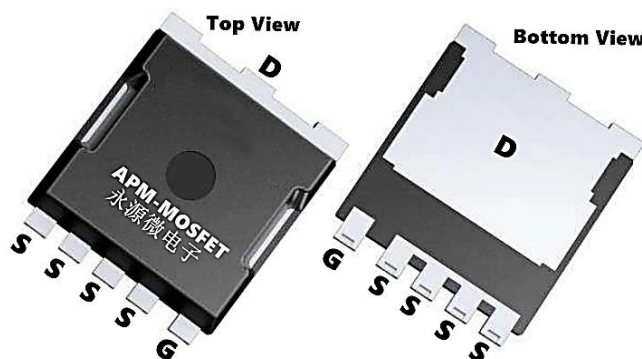
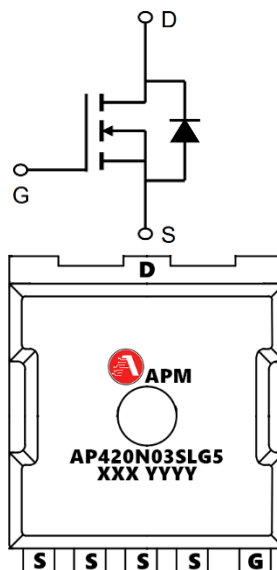
$V_{DS} = 30V$ $I_D = 420A$

$R_{DS(ON)} < 0.8m\Omega$ @ $V_{GS}=10V$ (Type: **0.55mΩ**)

Application

Buck

Boost



Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP420N03SLG5	STOLL-6L	AP420N03SLG5 XXX YYYY	2000

Absolute Maximum Ratings ($T_C=25^{\circ}C$ unless otherwise noted)

Symbol	Parameter	Max.	Units
V_{DSS}	Drain-Source Voltage	30	V
V_{GSS}	Gate-Source Voltage	± 20	V
$I_{D@TC=25^{\circ}C}$	Continuous Drain Current, $V_{GS} @ 10V$	420	A
$I_{D@TC=100^{\circ}C}$	Continuous Drain Current, $V_{GS} @ 10V$	307	A
I_{DM}	Pulsed Drain Current	1312	A
E_{AS}	Single Pulsed Avalanche Energy	845	mJ
I_{AS}	Avalanche Current	125	A
$P_{D@TC=25^{\circ}C}$	Power Dissipation	160	W
T_J TSTG	Operating Junction Temperature Range	-55 to 150	$^{\circ}C$
$R_{\theta JA}$	Thermal Resistance Junction-Ambient ¹	25	$^{\circ}C/W$
$R_{\theta JC}$	Thermal Resistance, Junction to Case	0.78	$^{\circ}C/W$

30V N-Channel Enhancement Mode MOSFET

Electrical Characteristics ($T_J=25^{\circ}\text{C}$, unless otherwise noted)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
V(BR)DSS	Drain-Source Breakdown Voltage	$V_{GS} = 0V, I_D = 250\mu A$	30	-	-	V
IGSS	Gate-body Leakage Current	$V_{DS} = 0V, V_{GS} = \pm 20V$	-	-	± 100	nA
IDSS	Zero Gate Voltage Drain Current $T_J=25^{\circ}\text{C}$	$V_{DS} = 30V, V_{GS} = 0V$	-	-	1	μA
	Zero Gate Voltage Drain Current $T_J=100^{\circ}\text{C}$		-	-	100	
VGS(th)	Gate-Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250\mu A$	1.2	1.6	2.5	V
RDS(on)	Drain-Source On-Resistance ⁴	$V_{GS} = 10V, I_D = 20A$	-	0.55	0.80	m Ω
		$V_{GS} = 4.5V, I_D = 10A$	-	0.90	1.2	
gfs	Forward Transconductance ⁴	$V_{DS} = 10V, I_D = 20A$	-	110	-	S
Ciss	Input Capacitance	$V_{DS} = 15V, V_{GS} = 0V, f = 1MHz$	-	6790	-	pF
Coss	Output Capacitance		-	2450	-	
Crss	Reverse Transfer Capacitance		-	220	-	
Rg	Gate Resistance	$f = 1MHz$	-	2.2	-	Ω
Qg	Total Gate Charge	$V_{GS} = 10V, V_{DS} = 15V, I_D = 20A$	-	109.3	-	nC
Qgs	Gate-Source Charge		-	20.8	-	
Qgd	Gate-Drain Charge		-	15.2	-	
td(on)	Turn-On Delay Time	$V_{GS} = 10V, V_{DD} = 15V, R_G = 3\Omega, I_D = 20A$	-	12	-	ns
tr	Rise Time		-	12.3	-	
td(off)	Turn-Off Delay Time		-	88.4	-	
tf	Fall Time		-	42.8	-	
trr	Body Diode Reverse Recovery Time	$I_F = 20A, dI/dt = 100A/\mu s$	-	72	-	ns
Qrr	Body Diode Reverse Recovery Charge		-	36	-	nC
VSD	Diode Forward Voltage ⁴	$I_S = 20A, V_{GS} = 0V$	-	-	1.2	V
IS	Continuous Source Current	$T_C = 25^{\circ}\text{C}$	-	-	240	A

Note :

- 1、The data tested by surface mounted on a 1 inch 2 FR-4 board with 20Z copper.
- 2、The data tested by pulsed , pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$
- 3、The EAS data shows Max. rating . The test condition is $V_{DD} = 25V, V_{GS} = 10V, L = 0.1mH, I_{AS} = 125A$
- 4、The power dissipation is limited by 150°C junction temperature
- 5、The data is theoretically the same as I_D and I_{DM} , in real applications , should be limited by total power dissipation.

Typical Characteristics

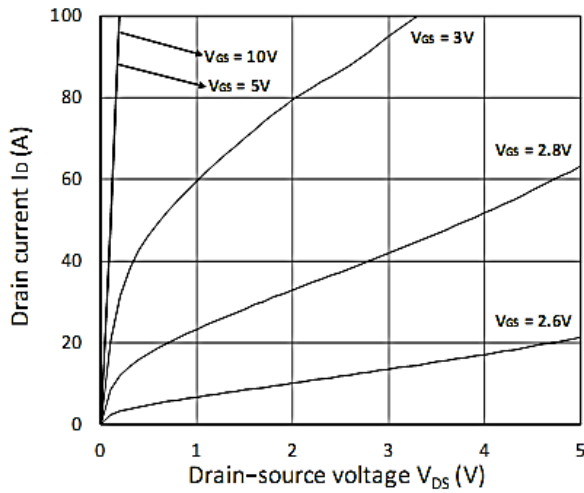


Figure 1. Output Characteristics

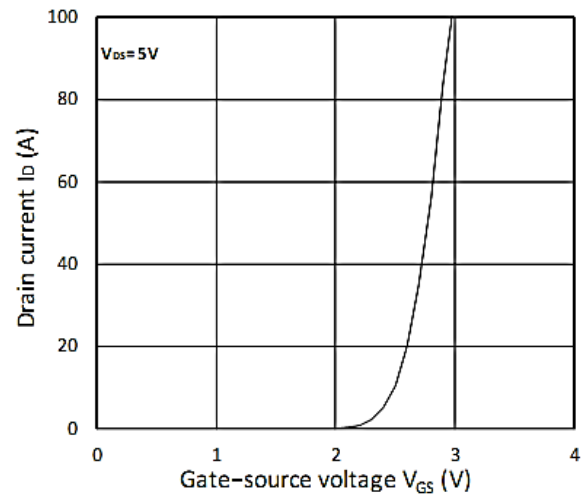


Figure 2. Transfer Characteristics

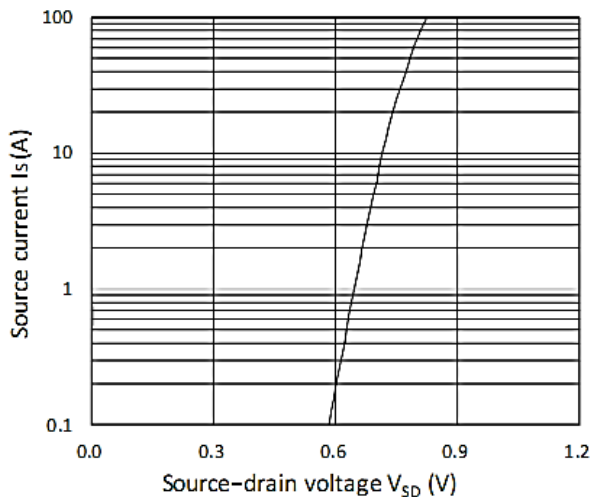


Figure 3. Forward Characteristics of Reverse

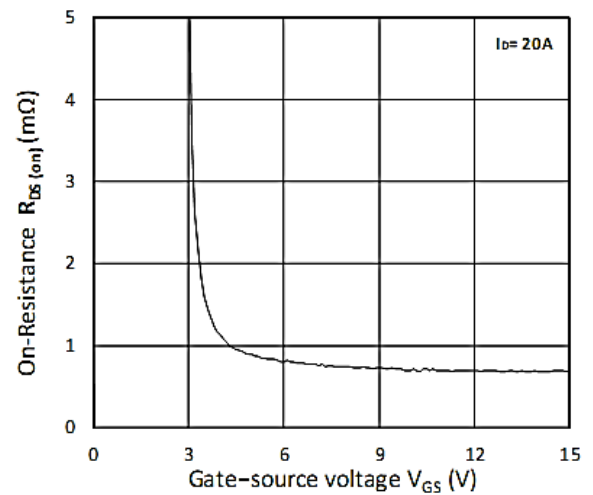


Figure 4. $R_{DS(ON)}$ vs. V_{GS}

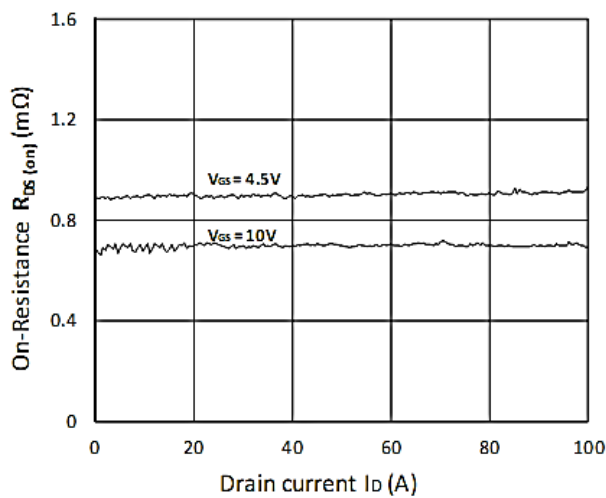


Figure 5. $R_{DS(ON)}$ vs. I_D

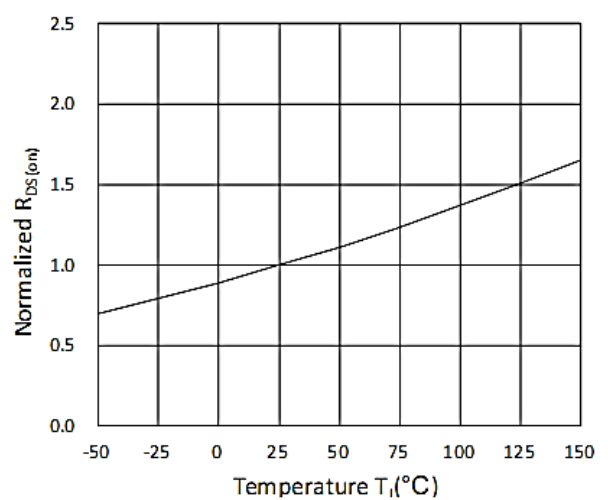


Figure 6. Normalized $R_{DS(on)}$ vs. Temperature



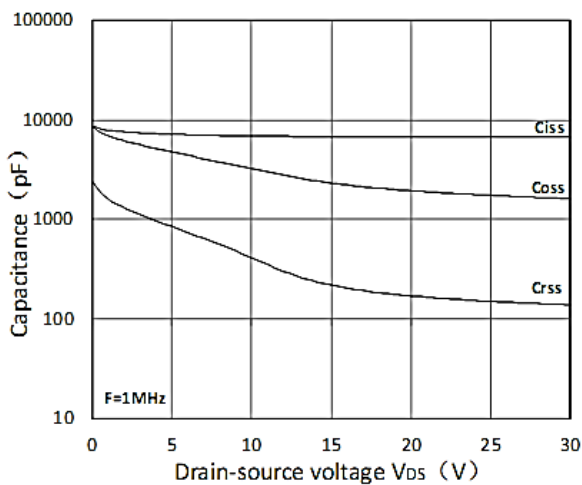


Figure 7. Capacitance Characteristics

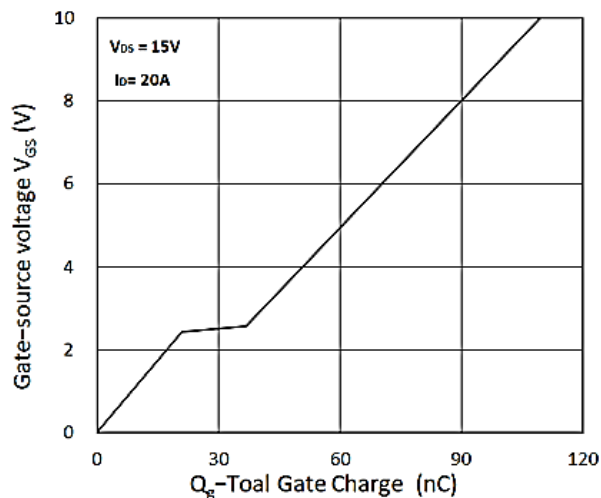


Figure 8. Gate Charge Characteristics

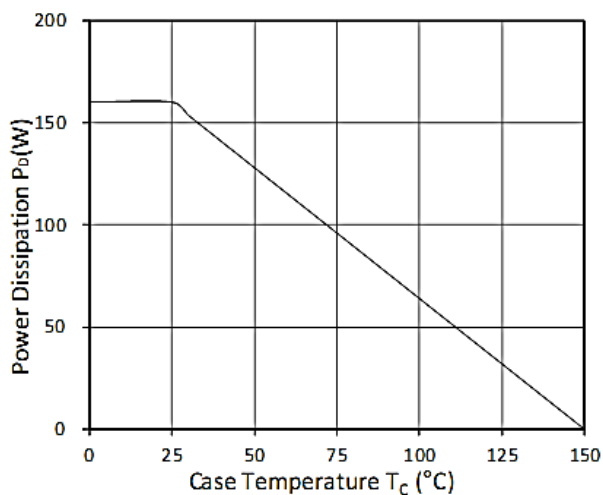


Figure 9. Power Dissipation

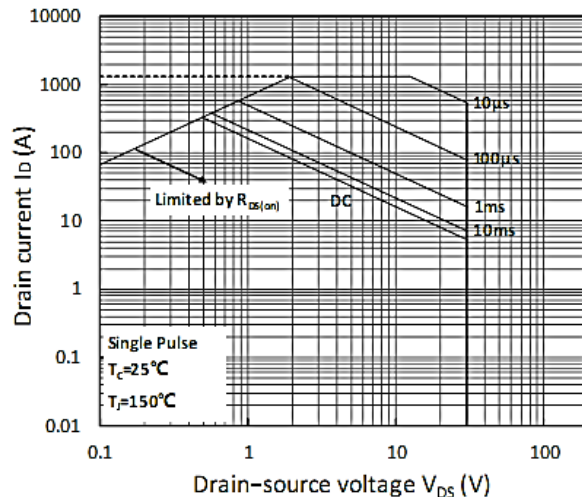


Figure 10. Safe Operating Area

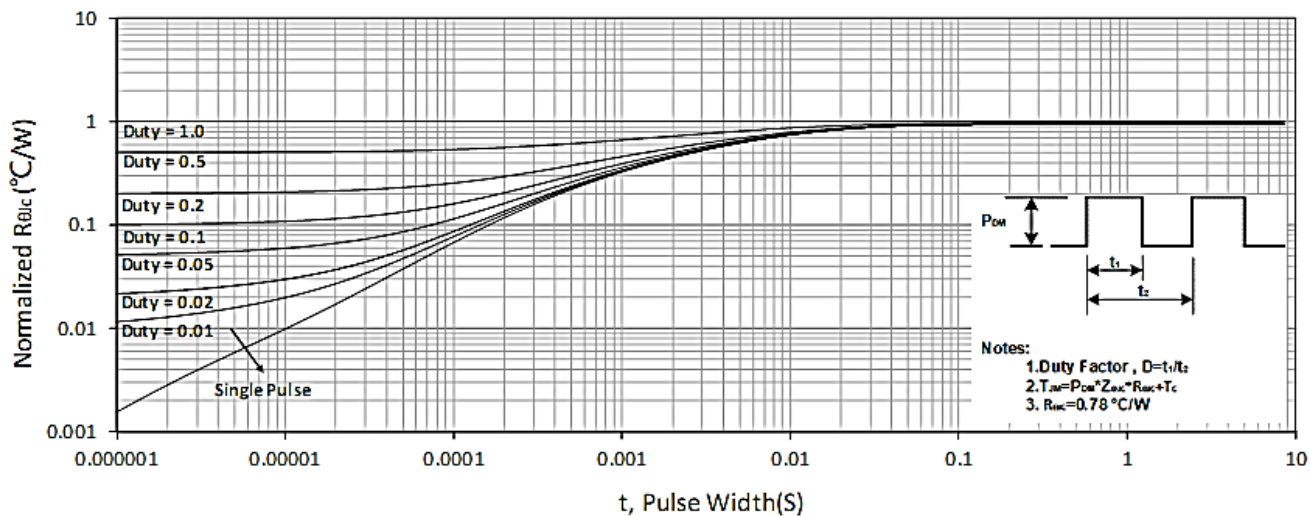
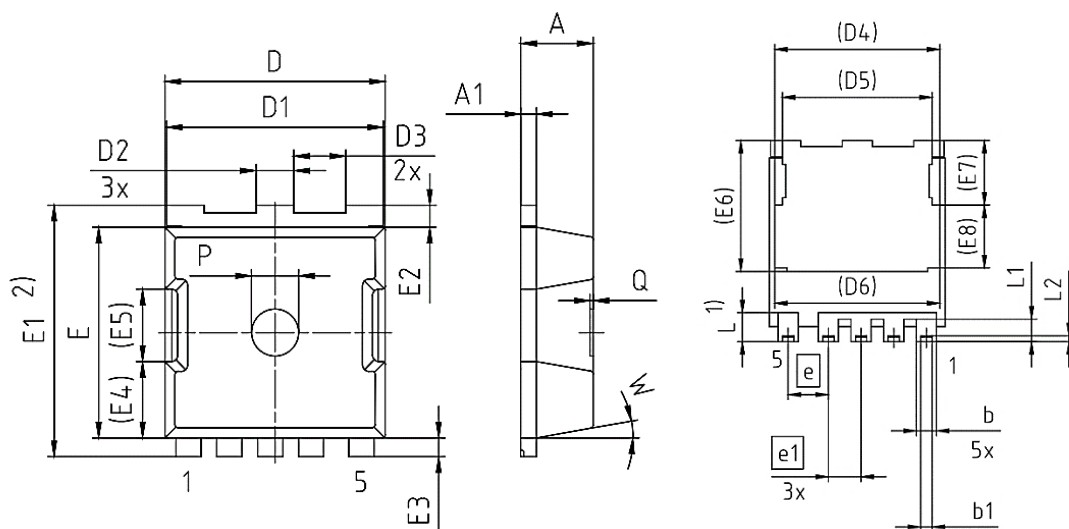


Figure 9 Normalized Maximum Transient Thermal Impedance

Package Mechanical Data-STOLL-6L-JJ Single



Symbol	Dimensions In Millimeters	
	Min.	Max.
A	2.2	2.4
A1	0.40	0.60
b	0.70	0.90
b1	0.42	0.50
D	6.80	7.20
D1	6.80	7.00
D2	1.10	1.30
D3	1.55	1.75
D4	6.56	
D5	5.96	
D6	5.60	
E	6.50	6.90
E1	7.80	8.20
E2	0.60	0.80
E3	0.50	0.70
E4	2.43	
E5	2.30	
E6	5.20	
E7	2.57	
E8	2.50	
e	1.60	
e1	1.30	
L	1.05	1.25
L1	0.80	1.00
L2	0.13	0.33
P	1.40	1.60
Q	0.00	0.10
W	8.50°	11.50°

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Edition	Date	Change
REV1.0	2023/3/31	Initial release

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